

High Speed Vlsi Architecture For Proposed Novel Adiabatic Encoder And Decoder

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ABSTRACT: *In this paper Sample adaptive encoder architecture is used as new in-loop filtering block. Exhaustive operations are performed to get the optimum AO parameters because of the huge amount of samples. In this paper we propose an High speed and low power Encoder Decoder of rate $\frac{1}{2}$ convolutional coding with a constraint length $K = 3$. At last we justify that using both logics in one Integrated Circuit (IC) we can create a high speed and low power Proposed encoder decoder with some extra hardware area*

KEY WORDS: in-loop filtering, sample adaptive encoder, high efficiency video coding.

I.INTRODUCTION

One of the main problem in real time communication is repetition of corrupt messages. Here the data should be delivered with low delay and the use of techniques will avoid the overloads by transmitting. During the digital information transmitting through a channel, practically inevitable errors are produced. To ensure reliable transmission, the data are further encoded via Error Correcting Code (ECC). This could be used to recognize and correct errors. In this work the well-known binary linear block Hamming codes are used because they have been used in the optimization problems that we accelerate thanks to the circuit explained further on. A binary linear (N, k) code is a k -dimensional subspace of the space of N -bit codewords, and therefore has 2^k codewords. But we solve for blocks or subsets of M codewords in the code, where $M \leq 2^k$, used to transmit a message. When a message is transmitted, its binary string can suffer modifications (changed bits), arriving an incorrect codeword in the receiver side.

As technology scales, reliability becomes a challenge for CMOS circuits. Reliability issues appear, for example during device Manufacturing, as defects that can compromise production yield. Once the devices are in the field, other reliability issues appear in the form of soft errors or age induced permanent failures. Memory devices are among those affected by those issues due to their high level of integration. Current techniques to address those reliability issues in memories include the use of redundant elements to repair manufacturing defects, and the use of Error Correcting Codes (ECC) to deal with soft errors once the device is in operation. Different techniques are used to deal with defects versus soft errors. ECC can also be used to correct errors caused by defects, but then their ability to correct soft errors may be compromised leading to a reduced reliability. However, to the best of our knowledge, there is no previous work on how the use of ECC to deal with defects affects the reliability of memory in the field.

Networking applications require high-speed processing of data and thus rely on complex integrated circuits. In routers and switches, packets typically enter the device through one port, are processed, and are then sent to one or more output ports. During this processing, data are stored and moved through the device. Reliability is a key requirement for networking equipment such as core routers. Therefore, the stored data must be protected to detect and correct errors. This is commonly done using error-correcting codes (ECCs). One problem that occurs when protecting the data in networking applications is that, to facilitate

its processing, a few control bits are added to each data block. For example, flags to mark the start of a packet (SOP), the end of a packet (EOP), or an error (ERR) are commonly used. These flags are used to determine the processing of the data, and the associated control logic is commonly on the critical timing path. To access the control bits, if they are protected with an ECC, they must first be decoded. This decoding adds delay and may limit the overall frequency. Several codes are used to evaluate the proposed method. After evaluation it is compared with the existing solutions in terms of decoding delay and area.

II. EXISTED SYSTEM

The below figure (1) shows the architecture of existed system. The existed architecture of SAO encoder is divided to three modules they are Statistics collection module, parameters determination module and controller. Let us discuss each module in detail.

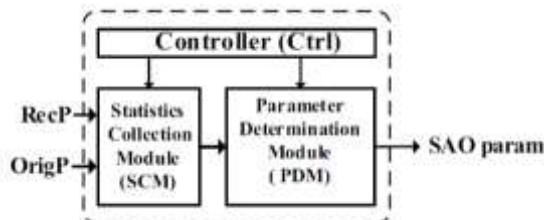


Fig. 1. Existed system

The SCM produces N and E of 4X4 pixels per cycle as follows. Each cycle consists of 6X6 RecP and 4X4 OrigP. These are registered to SCM. A signed difference (D)

Between OrigP and RecP is generated and clipped into $-7 \sim 7$ through subtractor and clipper module. An allocator is used to reorder RecP and D to be inputted to both EO and BO engines. Each EO class x engine works on the corresponding allocator output, it mainly consists of four Cat.x matching sub modules. This is about

SCM module, let us discuss about PDM module.

PDM works for 56 cycles to produce the optimum SAO parameters of the current CTB. Parameter determination module consists of four cores, E and N components. This component generates Minimum cost and offset generator and Group & Compare core (GAC) plus storage elements. Next one is controller, it works for reducing switching activity and the power consumption of the SAO encoder. Controller inputs data and triggers clock when required. The Clock gating technique is adopted to ensure pipelining. But this system does not produce better results so a new system is proposed which is discussed in below section.

III. PROPOSED SYSTEM

In this paper we proposed a design of high speed low power encoder/decoder at the RTL level in the standard cell design environment. In the standard cell design environment, the behaviour of a design is described in VHDL. The behavioural design is synthesized to generate a gate level design. The gate-level design is placed and routed to generate a layout of the design. The advantages of a standard cell based design over full custom design are faster turnaround time for the design, ease in design verification and more accurate modelling of the circuit. From below figure (2) we can observe the proposed encoder architecture.

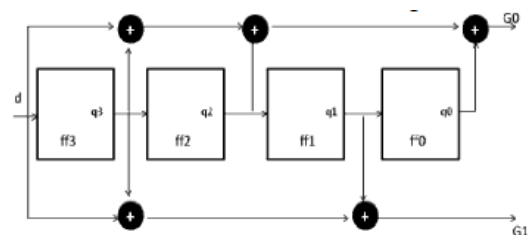


Fig. 2. . Proposed encoder

The encoder produces two bits of encoded information for each bit of input information, so it is called a rate 1/2 encoder. A convolutional encoder is generally characterized in (n, k, m) format, where n is number of outputs of the encoder; k is number of inputs of the encoder; m is number of memory elements (flip-flops) of the longest shift register of the encoder. The rate of a (n, k, m) encoder is k/n . From below figure (3) we can observe the proposed decoder architecture.

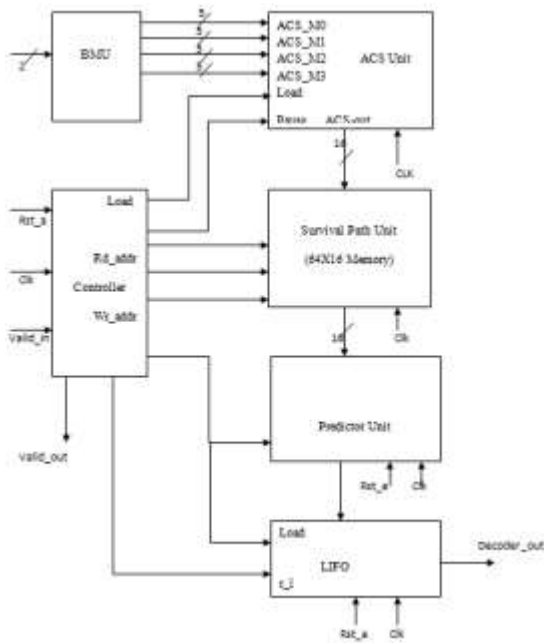


Fig. 3. Proposed decoder.

This section discusses the different parts of the proposed decoding process. Analog signals are quantized and converted into digital signals in the quantization block. We assume that a proposed decoder receives parallel successive code symbols, in which the boundaries of the symbols and the frames have been identified. Let us discuss about each unit in detail manner.

The BM unit is used to calculate branch metric for all trellis branches from the input data. We choose absolute difference

as measure for branch metric. These branch metrics are viewed as being the weights of the branches. The Add-Compare-Select (ACS) unit is the module that consumes the most power and area. Memory is required to store the survivor Path Matrix Unit (PMU) and the memory used is dual port. One port for writing the data and other for reading the data. A controller is used to synchronize between the different modules of the system. Predictor unit uses the state value to access a bit from the path metric memory unit (PMM). LIFO unit has 2 32-bit registers in which one of the register is read while the other is written.

IV. RESULTS



Fig. 4. RTL Schematic

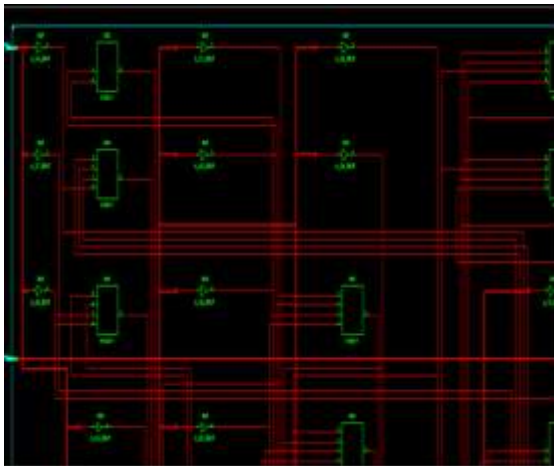


Fig. 5. Technology schematic

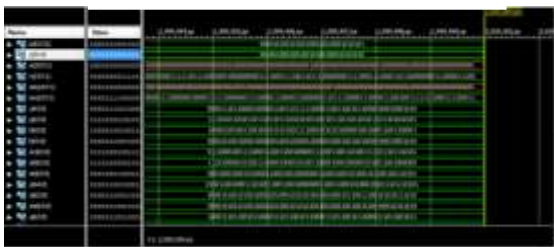


Fig. 6. Output waveform

V. CONCLUSION

In this paper a low cost high throughput high performance VLSI architecture for SAO encoding stage is presented. Our proposed encoder decoder architecture designs a high speed and power consumption decoder. For high speed data transmission communication protocols are used. At last compared to existed system, the proposed system gives better efficiency.

VI. REFERENCES

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